

Sixty-first Denver X-ray Conference and selected papers for the special June *Powder Diffraction* issue

This issue of *Powder Diffraction* is comprised of selected papers presented at the 2012 61st annual Denver X-ray Conference (DXC). At DXC 13 workshops, two poster sessions, a plenary session *New Frontiers in X-ray Analysis – Dedicated to the life and work of Robert L. Snyder*, and 13 special sessions were held, covering the following topics:

Cultural Heritage, Stress Analysis, Fusion and Industrial Applications of XRF, New Developments in XRD and XRF Instrumentation, Improved Fundamental Parameters, Rietveld Analysis, Industrial Applications and Energy Materials, Handheld XRF Applications, Trace Analysis, Line Profile Analysis, Quantitative Analysis, and Micro XRF.

As part of the Denver Conference, proceedings are published and from these proceedings, select papers covering XRD, XRF, and other high-energy scattering methods were selected for publication in *Powder Diffraction*. This issue of *Powder Diffraction* will provide readers with the opportunity to learn about current topics in a variety of materials characterization applications.

The talents of many people are required to make this special issue possible. Besides the authors themselves, we thank current and emeritus DXC organizing committee members for their reviews of these articles. We would also like to thank the DXC conference coordinator Denise Flaherty, *Powder Diffraction* managing editor Nicole Ernst-Boris, and *Powder Diffraction* Editor-in-Chief Ting Huang for all of their hard work in making this publication a reality. We hope you enjoy this compilation of manuscripts and we look forward to seeing you at the 2013 Denver X-ray Conference in Westminster, Colorado 5–9 August, 2013 (www.dxcicdd.com).

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